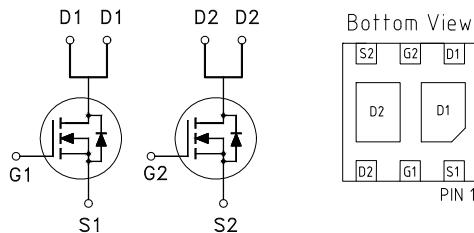


**Dual N-Channel Logic Level Enhancement Mode Field Effect Transistor**
**Product Summary:**

$BV_{DSS}$	20V
$R_{DS(on)}(\text{MAX.})$	45m $\Omega$
$I_D$	4.8A


**Pb-Free Lead Plating & Halogen Free**

**ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNIT
Gate-Source Voltage	$V_{GS}$	$\pm 12$	V
Continuous Drain Current	$I_D$	4.8	A
		3.8	
Pulsed Drain Current <sup>1</sup>	$I_{DM}$	19.2	
Power Dissipation	$P_D$	1.9	W
		1.2	
Operating Junction & Storage Temperature Range	$T_j, T_{stg}$	-55 to 150	°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	$R_{\theta JC}$	15	65	°C / W
Junction-to-Ambient <sup>3</sup>	$R_{\theta JA}$			

<sup>1</sup>Pulse width limited by maximum junction temperature.

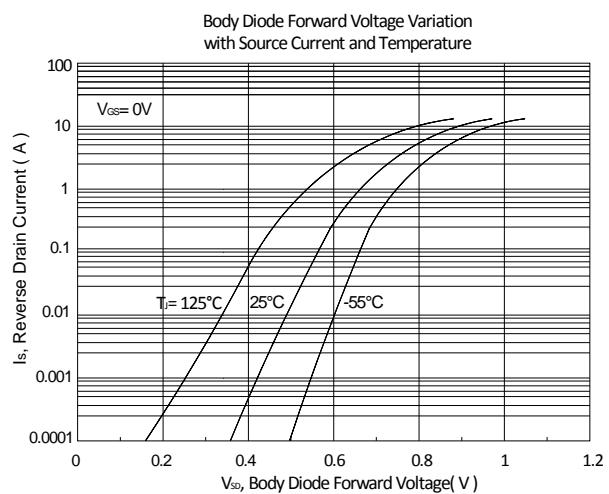
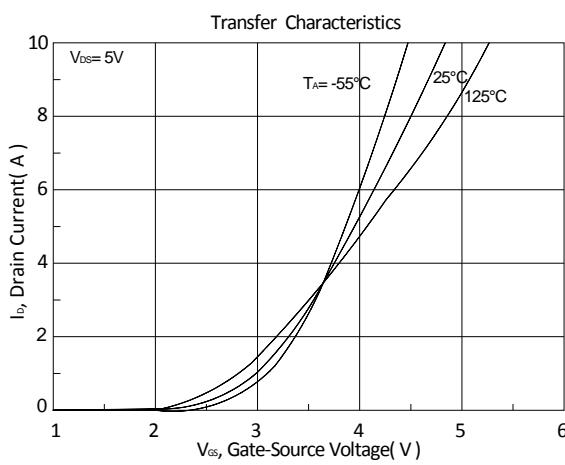
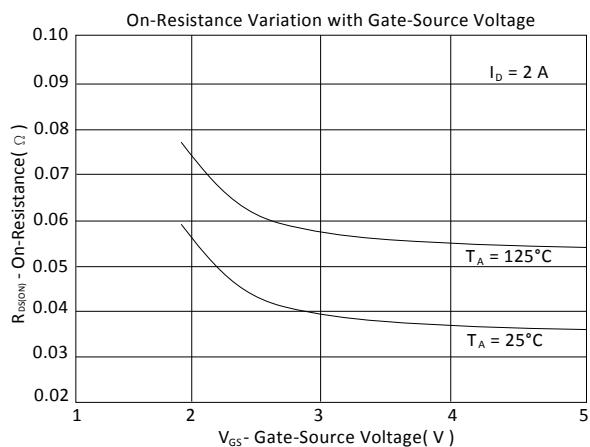
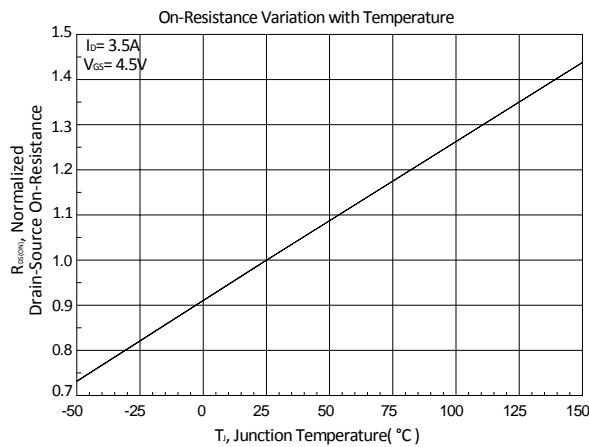
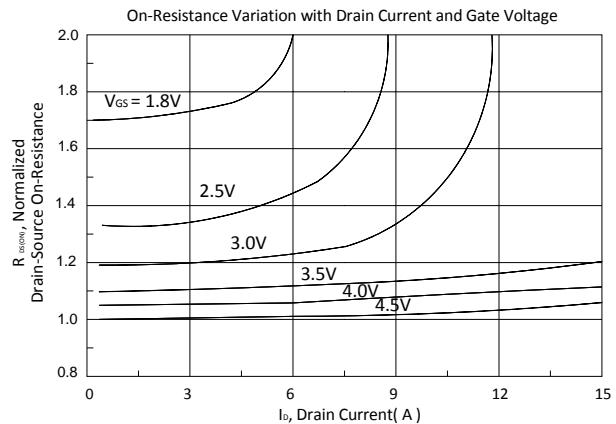
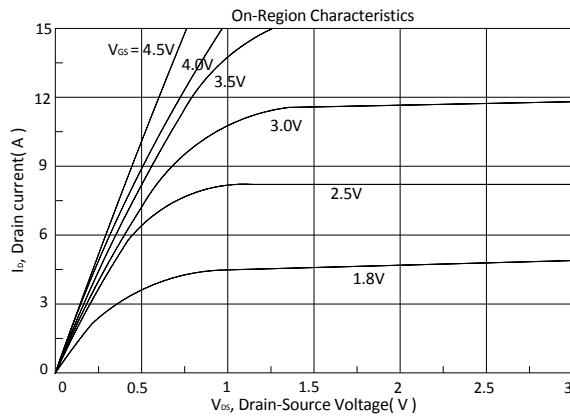
<sup>2</sup>Duty cycle  $\leq 1\%$ 
<sup>3</sup>65°C / W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.

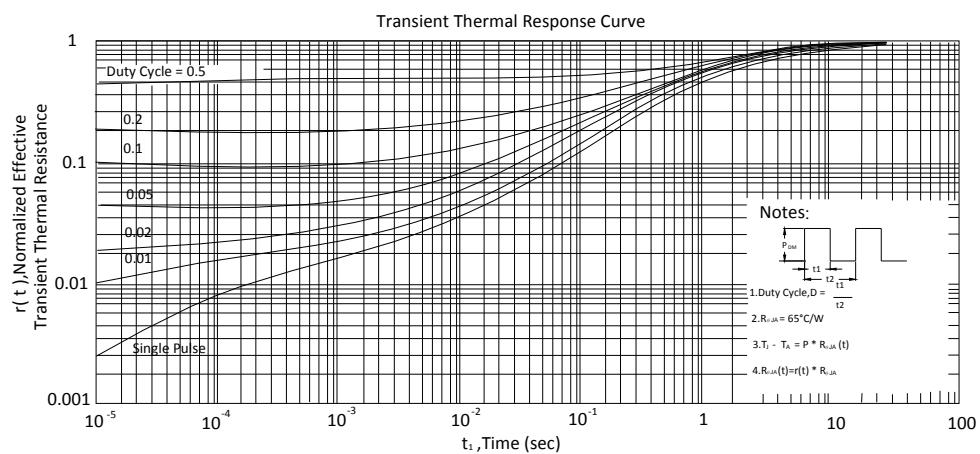
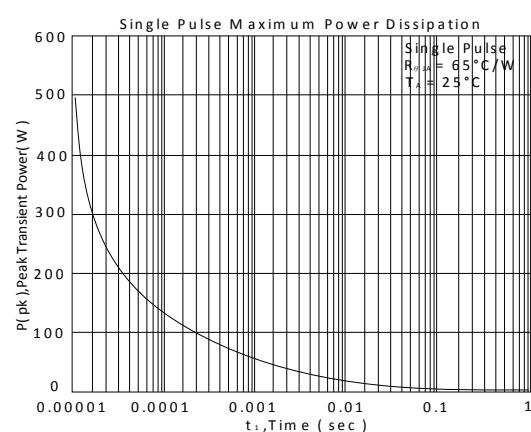
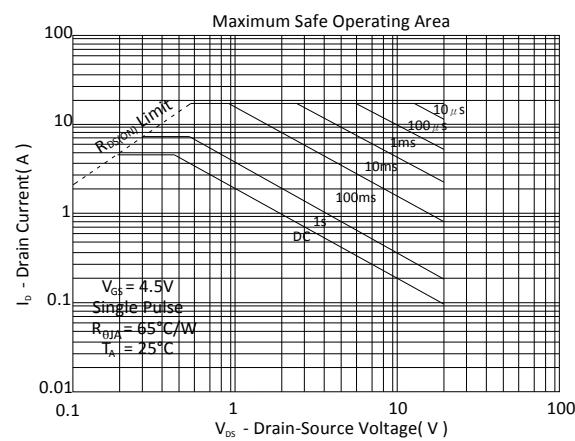
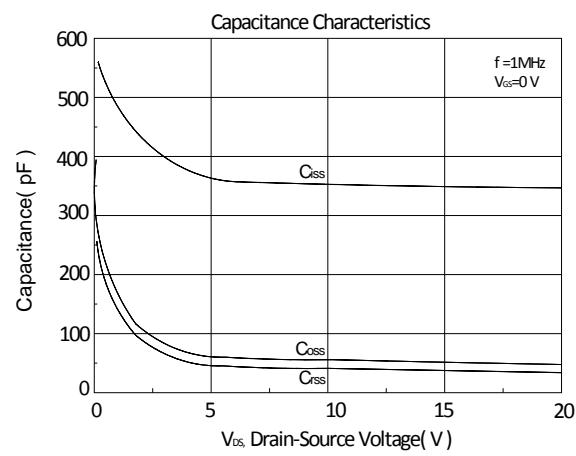
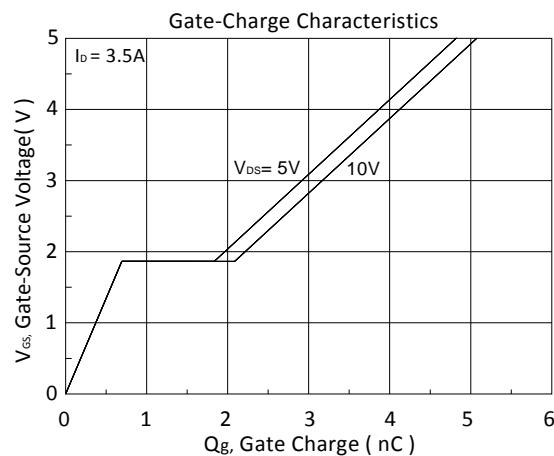
**ELECTRICAL CHARACTERISTICS (T<sub>J</sub> = 25 °C, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	20			V
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	0.4	0.75	1.2	
Gate-Body Leakage	I <sub>GSS</sub>	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±12V			±100	nA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 16V, V <sub>GS</sub> = 0V			1	μA
		V <sub>DS</sub> = 16V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 125 °C			25	
On-State Drain Current <sup>1</sup>	I <sub>D(ON)</sub>	V <sub>DS</sub> = 5V, V <sub>GS</sub> = 10V	4.8			A
Drain-Source On-State Resistance <sup>1</sup>	R <sub>D(S)ON</sub>	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 3.5A		36	45	mΩ
		V <sub>GS</sub> = 2.5V, I <sub>D</sub> = 2A		43	60	
		V <sub>GS</sub> = 1.8V, I <sub>D</sub> = 1A		58	85	
Forward Transconductance <sup>1</sup>	g <sub>f</sub>	V <sub>DS</sub> = 5V, I <sub>D</sub> = 3.5A		5		S
<b>DYNAMIC</b>						
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 10V, f = 1MHz		355		pF
Output Capacitance	C <sub>oss</sub>			56		
Reverse Transfer Capacitance	C <sub>rss</sub>			40		
Gate Resistance	R <sub>g</sub>	V <sub>GS</sub> = 15mV, V <sub>DS</sub> = 0V, f = 1MHz V <sub>DS</sub> = 10V, V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 3.5A		3.2		Ω
Total Gate Charge <sup>1,2</sup>	Q <sub>g</sub>			4.6		nC
Gate-Source Charge <sup>1,2</sup>	Q <sub>gs</sub>			0.66		
Gate-Drain Charge <sup>1,2</sup>	Q <sub>gd</sub>			1.5		
Turn-On Delay Time <sup>1,2</sup>	t <sub>d(on)</sub>	V <sub>DS</sub> = 10V, I <sub>D</sub> = 1A, V <sub>GS</sub> = 4.5V, R <sub>GS</sub> = 6Ω		8		nS
Rise Time <sup>1,2</sup>	t <sub>r</sub>			10		
Turn-Off Delay Time <sup>1,2</sup>	t <sub>d(off)</sub>			20		
Fall Time <sup>1,2</sup>	t <sub>f</sub>			15		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (T<sub>C</sub> = 25 °C)</b>						
Continuous Current	I <sub>S</sub>				4.8	A
Pulsed Current <sup>3</sup>	I <sub>SM</sub>				19.2	
Forward Voltage <sup>1</sup>	V <sub>SD</sub>	I <sub>F</sub> = I <sub>S</sub> , V <sub>GS</sub> = 0V			1.2	V

<sup>1</sup>Pulse test : Pulse Width ≤ 300 μsec, Duty Cycle ≤ 2%.<sup>2</sup>Independent of operating temperature.<sup>3</sup>Pulse width limited by maximum junction temperature.

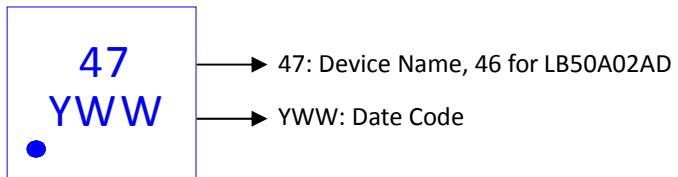
TYPICAL CHARACTERISTICS



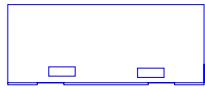
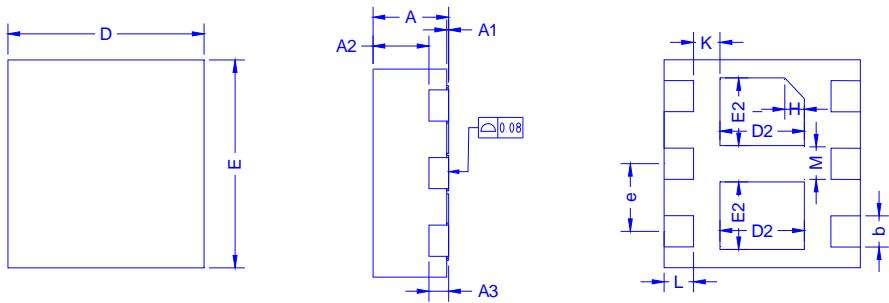


### Ordering & Marking Information:

Device Name: LB50A02AD for EDFN 2 x 2



### Outline Drawing



Dimension in mm

Dimension	A	A1	A2	A3	b	D	E	D2	E2	e	H	K	L	M
Min.	0.70	0.00	0.50	0.20 REF	0.25	1.90	1.90	0.76	0.55	0.55	0.20 REF	0.17	0.25	0.25
Max.	0.80	0.05	0.60		0.35	2.10	2.10	0.96	0.75	0.75		0.37	0.35	0.45

### Recommended minimum pads

